IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Ning

Docket No.:

01P7422 US

Serial No.:

09/854,760

Art Unit:

1756

Filed:

May 14, 2001

Examiner:

Vinh, Lan

Title:

Design Lithography Alignment and Overlay Measurement Marks on CMP

Finished Damascene Surface

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

RESPONSE UNDER 37 CFR 1.111

Dear Sir:

The following amendments and remarks are presented in response to the Examiner's Office Action mailed on June 10, 2003. They are respectfully submitted as a fully and complete response to that Office Action. Favorable consideration of the above-referenced patent application is respectfully requested.